

TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74HC4075AP, TC74HC4075AF

Triple 3-Input OR Gate

The TC74HC4075A is a high speed CMOS 3-INPUT OR GATE fabricated with silicon gate C²MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

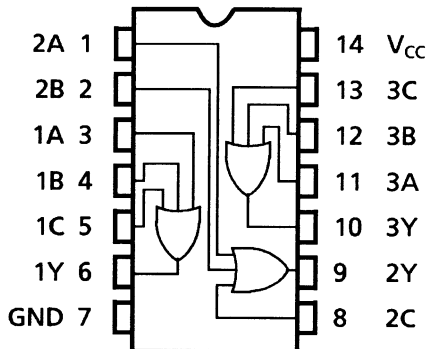
The internal circuit is composed of 4 stages including a buffered outputs, which provide high noise immunity and stable output.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

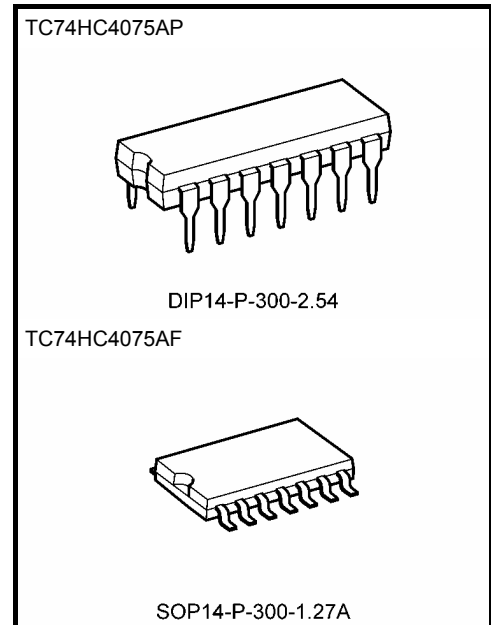
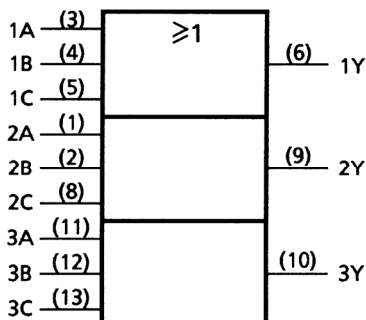
Features

- High speed: $t_{pd} = 8 \text{ ns}$ (typ.) at $V_{CC} = 5 \text{ V}$
- Low power dissipation: $I_{CC} = 2 \mu\text{A}$ (max) at $T_a = 25^\circ\text{C}$
- High noise immunity: $V_{NIH} = V_{NIL} = 28\% V_{CC}$ (min)
- Output drive capability: 10 LSTTL loads
- Symmetrical output impedance: $|I_{OH}| = I_{OL} = 4 \text{ mA}$ (min)
- Balanced propagation delays: $t_{pLH} \approx t_{pHL}$
- Wide operating voltage range: $V_{CC} \text{ (opr)} = 2 \text{ to } 6 \text{ V}$
- Pin and function compatible with 4075B

Pin Assignment



IEC Logic Symbol



Weight	
DIP14-P-300-2.54	: 0.96 g (typ.)
SOP14-P-300-1.27A	: 0.18 g (typ.)

Truth Table

A	B	C	Y
H	X	X	H
X	H	X	H
X	X	H	H
L	L	L	L

X: Don't care

Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V_{CC}	-0.5 to 7	V
DC input voltage	V_{IN}	-0.5 to $V_{CC} + 0.5$	V
DC output voltage	V_{OUT}	-0.5 to $V_{CC} + 0.5$	V
Input diode current	I_{IK}	± 20	mA
Output diode current	I_{OK}	± 20	mA
DC output current	I_{OUT}	± 25	mA
DC V_{CC} /ground current	I_{CC}	± 50	mA
Power dissipation	P_D	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T_{stg}	-65 to 150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of $T_a = -40$ to 65°C . From $T_a = 65$ to 85°C a derating factor of $-10\text{ mW}/^\circ\text{C}$ shall be applied until 300 mW.

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V_{CC}	2 to 6	V
Input voltage	V_{IN}	0 to V_{CC}	V
Output voltage	V_{OUT}	0 to V_{CC}	V
Operating temperature	T_{opr}	-40 to 85	°C
Input rise and fall time	t_r, t_f	0 to 1000 ($V_{CC} = 2.0\text{ V}$) 0 to 500 ($V_{CC} = 4.5\text{ V}$) 0 to 400 ($V_{CC} = 6.0\text{ V}$)	ns

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either V_{CC} or GND.

Electrical Characteristics
DC Characteristics

Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = -40 to 85°C		Unit
				V _{CC} (V)	Min	Typ.	Max	Min	Max
High-level input voltage	V _{IH}	—		2.0 4.5 6.0	1.50 3.15 4.20	— — —	— — —	1.50 3.15 4.20	V
Low-level input voltage	V _{IL}	—		2.0 4.5 6.0	— — —	— — —	0.50 1.35 1.80	— — —	V
High-level output voltage	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -20 µA	2.0 4.5 6.0	1.9 4.4 5.9	2.0 4.5 6.0	— — —	1.9 4.4 5.9	V
			I _{OH} = -4 mA	4.5	4.18	4.31	—	4.13	
			I _{OH} = -5.2 mA	6.0	5.68	5.80	—	5.63	
Low-level output voltage	V _{OL}	V _{IN} = V _{IH} or V _{IL}	I _{OL} = 20 µA	2.0 4.5 6.0	— — —	0.0 0.0 0.0	0.1 0.1 0.1	— — —	V
			I _{OL} = 4 mA	4.5	—	0.17	0.26	—	
			I _{OL} = 5.2 mA	6.0	—	0.18	0.26	—	
Input leakage current	I _{IN}	V _{IN} = V _{CC} or GND		6.0	—	—	±0.1	—	µA
Quiescent supply current	I _{CC}	V _{IN} = V _{CC} or GND		6.0	—	—	1.0	—	µA

AC Characteristics (C_L = 15 pF, V_{CC} = 5 V, Ta = 25°C, input: t_r = t_f = 6 ns)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Output transition time	t _{TLH}	—	—	4	8	ns
	t _{THL}					
Propagation delay time	t _{pLH}	—	—	8	15	ns
	t _{pHL}					

AC Characteristics ($C_L = 50 \text{ pF}$, input: $t_r = t_f = 6 \text{ ns}$)

Characteristics	Symbol	Test Condition	Ta = 25°C			Ta = -40 to 85°C		Unit
			V _{CC} (V)	Min	Typ.	Max	Min	Max
Output transition time	t _{TLH} t _{THL}	—	2.0	—	30	75	—	95
			4.5	—	8	15	—	19
			6.0	—	7	13	—	16
Propagation delay time	t _{pLH} t _{pHL}	—	2.0	—	35	90	—	115
			4.5	—	11	18	—	23
			6.0	—	9	15	—	20
Input capacitance	C _{IN}	—	—	—	5	10	—	10
Power dissipation capacitance	C _{PD} (Note)	—	—	—	27	—	—	—

Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

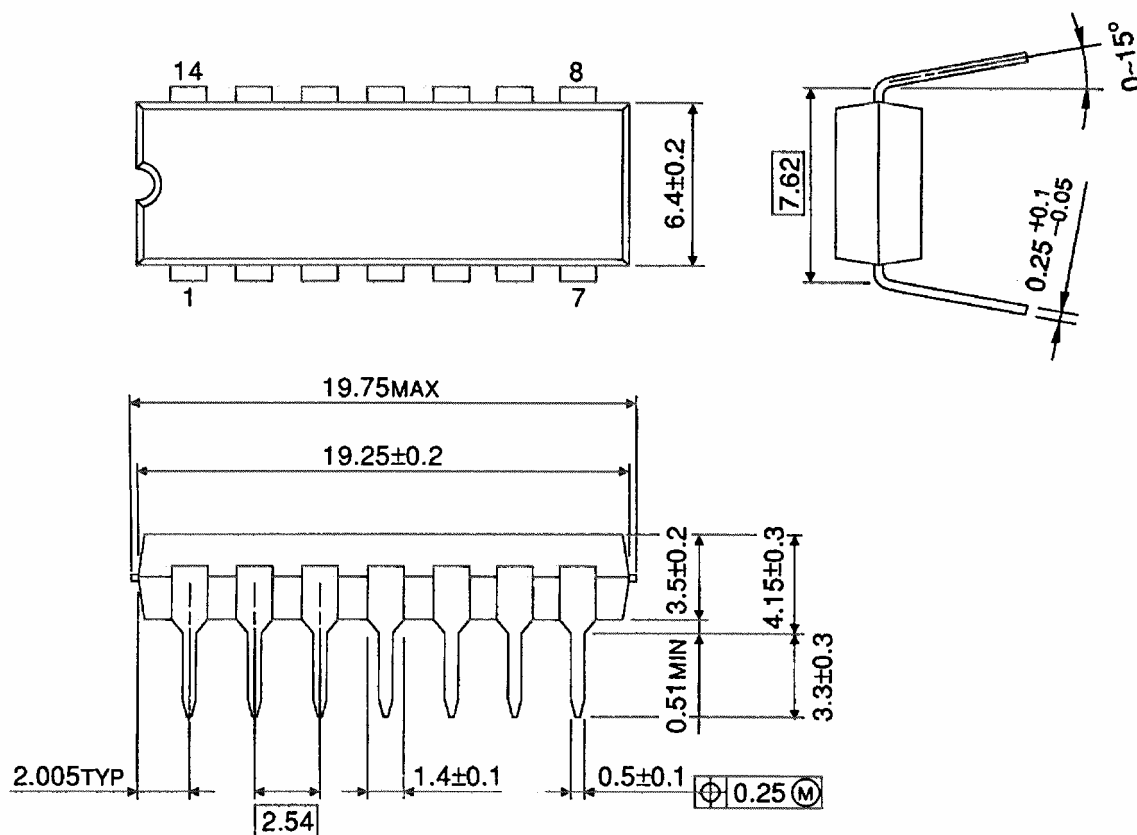
Average operating current can be obtained by the equation:

$$I_{CC}(\text{opr}) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/3 \text{ (per gate)}$$

Package Dimensions

DIP14-P-300-2.54

Unit : mm

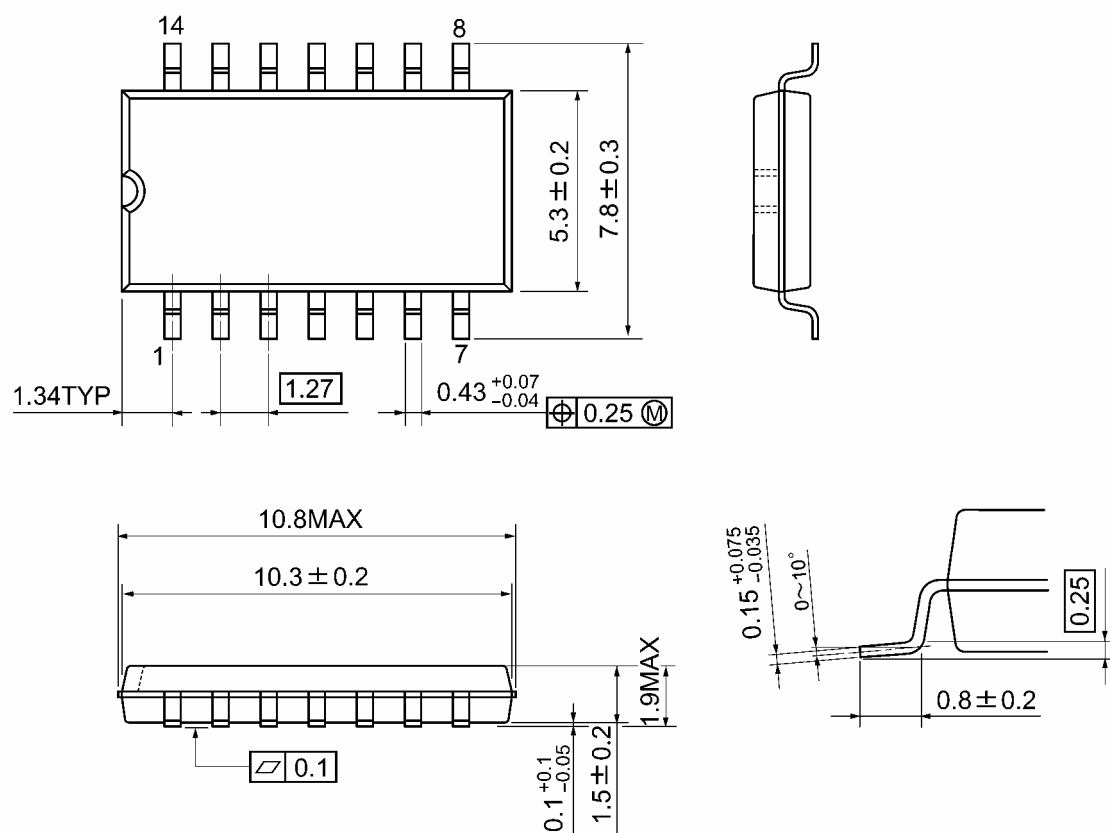


Weight: 0.96 g (typ.)

Package Dimensions

SOP14-P-300-1.27A

Unit: mm



Weight: 0.18 g (typ.)

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20070701-EN GENERAL

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